N-Channel Small Signal MOSFET

FEATURES

- Lower R_{DS(on)}
- Improved Inductive Ruggedness
- □ Fast Switching Times
- □ Lower Input Capacitance
- D Extended Safe Operating Area
- □ Improved High Temperature Reliability

Product Summary

Part Number	$\mathbf{BV}_{\mathrm{DSS}}$	R _{DS} (on)	I _D
2N7002	60V	5.0Ω	115mA

Absolute Maximum Ratings

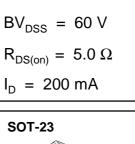
Symbol	Characteristic	Value	Units	
V _{DSS}	Drain-to-Source Voltage	60	V	
	Continuous Drain Current (T _c =25°C)	115	m /	
I _D Continuous Drain Current (T _c =100°C)		73	mA	
I _{DM}	Drain Current-Pulsed ①	800	mA	
V _{GS}	Gate-to-Source Voltage	±20	V	
	Total Power Dissipation (T _C =25°C)	0.2	W	
P _D	Linear Derating Factor	1.6	mW/℃	
	Operating Junction and		Ĵ	
T_J , T_STG	Storage Temperature Range	- 55 to +150	C	

Thermal Resistance

Symbol	Characteristic	Тур.	Max.	Units
$R_{\Theta JA}$	Junction-to-Ambient		625	СМ



2N7002MTF





2N7002MTF

Symbol	Characteristic	Min.	Тур.	Max.	Units	Test Condition	
BV _{DSS}	Drain-Source Breakdown Voltage	60	-	-	V	$V_{GS} = 0V, I_{D} = 250 \mu A$	
V _{GS(th)}	Gate Threshold Voltage	1.2	-	2.5	V	$V_{DS} = V_{GS}, I_D = 250 \mu A$	
	Gate-Source Leakage, Forward	-	-	100		V _{GS} = 20V	
I _{GSS}	Gate-Source Leakage, Reverse	-	-	-100	nA	V _{GS} = -20V	
	Drain to Course Lookage Current	-	-	1.0	μA	$V_{GS} = 40V$	
I _{DSS}	Drain-to-Source Leakage Current	-	-	500	μΛ	V _{GS} = 40V, T _C = 125℃	
I _{D(ON)}	On-State Drain-Source Current	0.5	-	-	А	$V_{DS} = 10V, V_{GS} = 10V$	
R _{DS(on)}	Static Drain-Source On-State Resistance (2)	-	-	5.0	Ω	$V_{GS} = 10V, I_{D} = 0.5A$	
9 _{fs}	Forward Transconductance 2	0.08	-	-	S	V _{DS} = 15V, I _D = 0.2A	
C _{iss}	Input Capacitance	-	-	50			
C _{oss}	Output Capacitance	-	-	25	pF	$V_{DS} = 25V, V_{GS} = 0V,$ f = 1.0MHz	
C _{rss}	Reverse Transfer Capacitance	-	-	5			
t _{d(on)}	Turn-On Delay Time	-	-	20			
t _r	Rise Time	-	-	-	$V_{DD} = 30V, I_D = 0.2A$		
t _{d(off)}	Turn-Off Delay Time	-	-	20	ns	R _G = 25Ω ②③	
t _f	Fall Time	-	-	-			

Electrical Characteristics (T_C=25 $^{\circ}$ C unless otherwise specified)

Source-Drain Diode Ratings and Characteristics

Symbol Characteristic		Min.	Тур.	Max.	Units	Test Condition
۱ _s	Continuous Source Current	-	-	115	mA	Integral reverse pn-diode
I _{SD}	Pulse Source Current ①	-	-	800	mA	In the MOSFET
V _{SD}	Diode Forward Voltage (2)	-	-	1.5	V	$T_A = 25$ °C, $I_S = 115mA$ $V_{GS} = 0V$

Notes;

1 Repetitive Rating : Pulse Width Limited by Maximum Junction Temperature

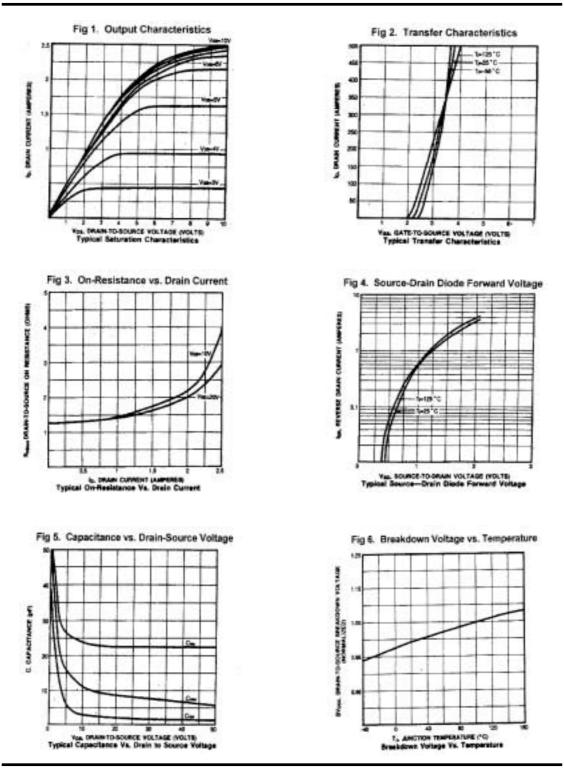
(2) Pulse Test : Pulse Width = 250 μ s, Duty Cycle \leq 2%

③ Essentially Independent of Operating Temperature



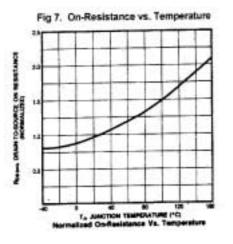
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Advance Information	Formative or In Design	This datasheet contains the design specifications for product development. Specifications may change in any manner without notice.
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